

**ON Semiconductor®** 

# FDN337N N-Channel Logic Level Enhancement Mode Field Effect Transistor

## **General Description**

SuperSOTTM-3 N-Channel logic level enhancement mode power field effect transistors are produced using ON Semiconductor's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications in notebook computers, portable phones, PCMCIA cards, and other battery powered circuits where fast switching, and low in-line power loss are needed in a very small outline surface mount package.

### Features

- 2.2 A, 30 V,  $R_{DS(ON)} = 0.065 \Omega @ V_{GS} = 4.5 V$  $R_{DS(ON)} = 0.082 \Omega @ V_{GS} = 2.5 V.$
- Industry standard outline SOT-23 surface mount package using proprietary SuperSOT<sup>™</sup>-3 design for superior thermal and electrical capabilities.
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- Exceptional on-resistance and maximum DC current capability.

S	OT-23 SuperSOT <sup>™</sup> -6	SuperSOT <sup>™</sup> -8	SO-8	SOT-223	SOIC-16				
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	SuperSOT <sup>™</sup> -3 G	05°0 uslass sthewise a		GS					
		= 25°C unless other wise n	oted	G S	Units				
Absoli ymbol	SuperSOT <sup>™</sup> -3 G	= 25°C unless other wise n	oted		Units				
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Absoli ymbol oss sss	SuperSOT <sup>™</sup> -3       G         ute Maximum Ratings       T <sub>A</sub> Parameter       Drain-Source Voltage         Gate-Source Voltage - Continuou       Continuou         Drain/Output Current - Continuou       - Pulsed         Maximum Power Dissipation       Maximum Power Dissipation	JS JS (Note 1a) (Note 1b)	oted	FDN337N           30           ±8           2.2           10           0.5           0.46	V           V           A           W				
Absoli ymbol bss css c p	G         Ute Maximum Ratings       T <sub>A</sub> Parameter       Drain-Source Voltage         Gate-Source Voltage - Continuou       Continuou         Drain/Output Current - Continuou       - Pulsed         Maximum Power Dissipation       Operating and Storage Temperation	JS JS (Note 1a) (Note 1b) ture Range		FDN337N           30           ±8           2.2           10           0.5           0.46	V           V           A           W				

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS		•	•		
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_{\rm D}$ = 250 µA, Referenced to 25 °C		41		mV/ °C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{\rm DS} = 24 \ V, \ V_{\rm GS} = 0 \ V$			1	μA
		$T_{J} = 55^{\circ}C$			10	μA
	Gate - Body Leakage, Forward	$V_{GS} = 8 V, V_{DS} = 0 V$			100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{GS} = -8 V, V_{DS} = 0 V$			-100	nA
ON CHARA	CTERISTICS (Note)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, \ I_{D} = 250 \ \mu A$	0.4	0.7	1	V
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold Voltage Temp. Coefficient	$I_{\rm D}$ = 250 µA, Referenced to 25 °C		-2.3		mV/ °C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 2.2 \text{ A}$		0.054	0.065	Ω
		T <sub>J</sub> =125°C		0.08	0.11	
		$V_{GS} = 2.5 \text{ V}, I_{D} = 2 \text{ A}$		0.07	0.082	
I <sub>D(ON)</sub>	On-State Drain Current	$V_{GS} = 4.5 V, V_{DS} = 5 V$	10			Α
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 V, I_{D} = 2.2 A$		13		S
DYNAMIC C	HARACTERISTICS					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		300		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		145		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			35		pF
SWITCHING	CHARACTERISTICS (Note)					
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{\text{DD}} = 5 \text{ V}, \ I_{\text{D}} = 1 \text{ A},$		4	10	ns
ţ,	Turn - On Rise Time	$V_{GS} = 4.5 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		10	18	ns
t <sub>D(off)</sub>	Turn - Off Delay Time			17	28	ns
t,	Turn - Off Fall Time			4	10	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 2.2 \text{ A},$ $V_{GS} = 4.5 \text{ V}$		7	9	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 4.5 V$		1.1		nC
Q <sub>gd</sub>	Gate-Drain Charge			1.9		nC
DRAIN-SO	JRCE DIODE CHARACTERISTICS AND M	IAXIMUM RATINGS				
l <sub>s</sub>	Maximum Continuous Drain-Source Diode Forward Current				0.42	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage $V_{GS} = 0 V$ , $I_S = 0.42 A$ (Note)			0.65	1.2	V

1. R<sub>BM</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>BM</sub> is guaranteed by design while R<sub>BCA</sub> is determined by the user's board design.

Typical  $\rm R_{_{\rm BJA}}$  using the board layouts shown below on FR-4 PCB in a still air environment :

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2.0%.

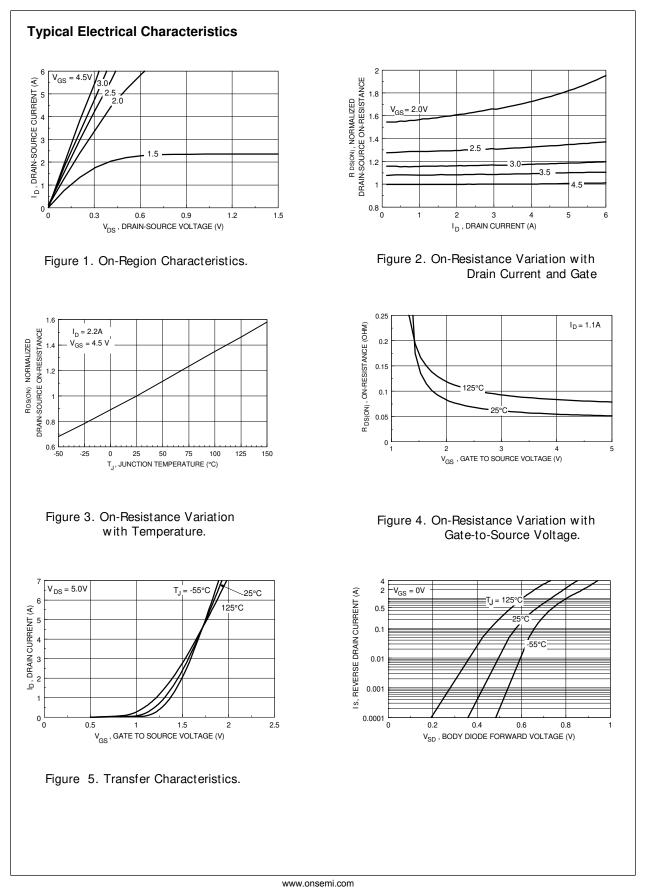


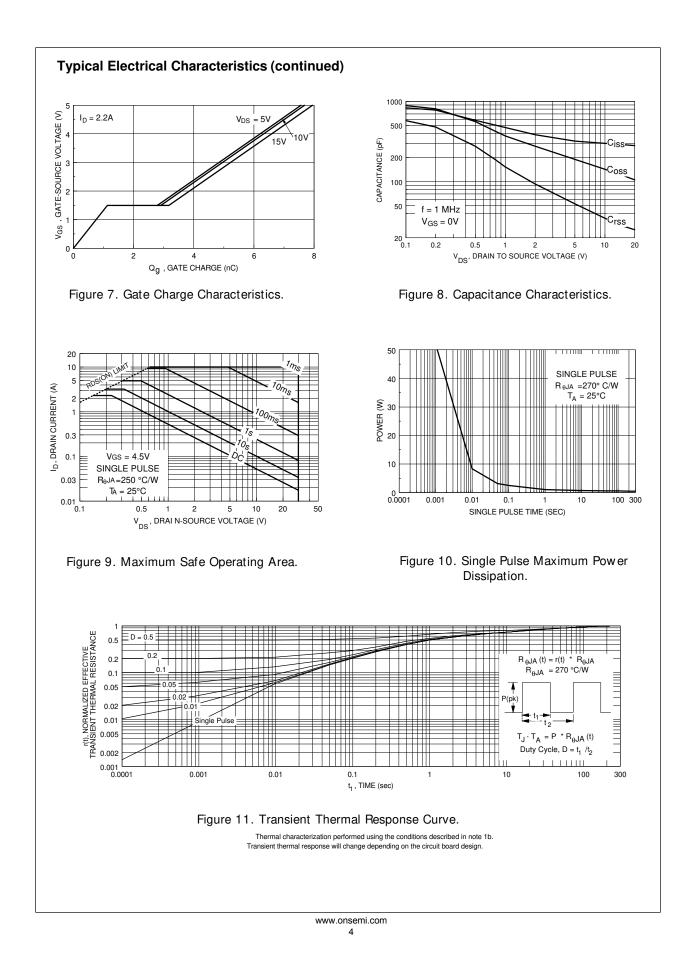
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a. 250°C/W when mounted on 0.02 in<sup>2</sup> pad of 2oz Cu.

b. 270°C/W when mounted on a 0.001 in<sup>2</sup> pad of 2oz Cu.

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